WHAT IS CLAIMED IS:

- 1. A copper alloy suitable for an IC lead pin for a pin grid array provided on a plastic substrate, which copper alloy is selected from the group consisting of:
- a copper alloy containing 0.05 to 0.5 wt% of Zn and 0.05 to 0.5 wt% of Mg, with the balance being made of unavoidable impurities and Cu;
- a copper alloy containing 0.1 to 1.0 wt% of Sn, with the balance being made of unavoidable impurities and Cu;
 - a copper alloy containing 0.1 to 1.0 wt% of Sn and 0.1 to 0.6 wt% of Ag, with the balance being made of unavoidable impurities and Cu;
- a copper alloy containing 2.1 to 2.6 wt% of Fe, 0.05

 15 to 0.2 wt% of Zn, and 0.015 to 0.15 wt% of P, with the

 balance being made of unavoidable impurities and Cu; and
 - a copper alloy containing 0.4 to 1.1 wt% of Cr, with the balance being made of unavoidable impurities and Cu,
- wherein the copper alloy has conductivity of 50% 20 IACS or more, and tensile stress of 400 MPa or more but 650 MPa or less.
- 2. The copper alloy as claimed in claim 1, which is the copper alloy containing 0.05 to 0.5 wt% of Zn and 0.05 to 0.5 wt% of Mg, with the balance being made of

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unavoidable impurities and Cu.

- 3. The copper alloy as claimed in claim 1, which is the copper alloy containing 0.1 to 1.0 wt% of Sn, with the balance being made of unavoidable impurities and Cu.
- 4. The copper alloy as claimed in claim 1, which is the copper alloy containing 0.1 to 1.0 wt% of Sn and 0.1 to 0.6 wt% of Ag, with the balance being made of unavoidable impurities and Cu.
- 5. The copper alloy as claimed in claim 1, which is the copper alloy containing 2.1 to 2.6 wt% of Fe, 0.05 to 0.2 wt% of Zn, and 0.015 to 0.15 wt% of P, with the balance being made of unavoidable impurities and Cu.
 - 6. The copper alloy as claimed in claim 1, which is the copper alloy containing 0.4 to 1.1 wt% of Cr, with the balance being made of unavoidable impurities and Cu.